## Notice of Réferences Cited

Application/Control No.

O9/828,575

Applicant(s)/Patent Under Reexamination SCHMIDT ET AL.

Examiner

Hae Moon Hyeon

Applicant(s)/Patent Under Reexamination SCHMIDT ET AL.

Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	Α	US-6371793	04-2002	Doorhy et al.	439/404
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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## **FOREIGN PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

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